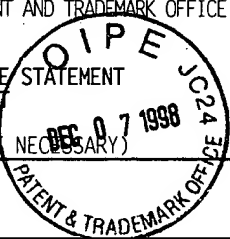


FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. IMEC88.001CP1	APPLICATION NO. 09/157,655
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Dierickx et al.	
		FILING DATE September 21, 1998	GROUP 2711 2878




U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
TXL		4,473,836	9/25/84	Chamberlain	257	290	—
TXL		4,565,756	1/21/86	Needs	430	7	—
TXL		4,580,103	4/1/86	Tompsett	330	9	—
TXL		4,647,975	3/3/87	Alston et al.	348	222	—
TXL		5,146,074	9/8/92	Kawahara et al.	250	208.1	—
TXL		5,153,420	10/6/92	Hack et al.	250	208.1	—
TXL		5,164,832	11/17/92	Halvis et al.	348	250	—
TXL		5,258,845	11/2/93	Kyuma et al.	348	299	—
TXL		5,296,696	3/22/94	Uno	250	208.1	—
TXL		5,321,528	6/14/94	Nakamura	358	482	—
TXL		5,335,008	8/2/94	Hamasaki	348	301	—
TXL		5,608,204	3/4/97	Hofflinger et al.	250	208.1	—
TXL		5,614,744	3/25/97	Merrill	257	291	—
TXL		3,904,818	9/9/75	Kovac	348	243	—
TXL		4,253,120	2/24/81	Levine	348	246	—

FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
TXL		548 987	6/30/93	Europe	—	—		
TXL		657 863	6/14/95	Europe	—	—		
TXL		739 039	10/23/96	Europe	—	—		
TXL		93/19489	9/30/93	PCT	—	—		
TXL		635 973	1/25/95	Europe	—	—		
TXL		260 954	3/23/88	Europe	—	—		
TXL		354 106	7/2/90	Europe	—	—		
TXL			4/8/98	European Search Report	—	—		

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
TXL ↓	Aoki et al., "A Collinear 3-Chip Image Sensor", <u>IEEE International Solid-State Circuits Conference</u> , 1985, pp. 102-103.
	Horii et al., "A 490 x 404 Element Imager for a Single-Chip Color Camera", <u>IEEE International Solid-State Circuits Conference</u> , 1985, pp. 96-97.
	Nagakawa et al., "A 580 x 500-Element CCD Imager with a Shallow Flat P Well", <u>IEEE International Solid-State Circuits Conference</u> , 1985, pp. 98-99.
	Mahowald, M.A., "Silicon Retina with Adaptive Photoreceptors", <u>SPIE</u> , Vol. 1473, 1991, pp. 52-58.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. IMEC88.001CP1	APPLICATION NO. 09/157,655
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EXAMINER INITIAL TXL 	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	Mann, J. "Implementing Early Visual Processing In Analog VLSI: Light Adaptation". <u>SPIE</u> , Vol 1473, 1991, pp. 128-136.
	Ono et al., "Analysis of Smear Noise In Interline-CCD Image Sensor with Gate-Free Isolation Structure", Abstract of the 1991 Int'l Conference on Solid State Devices and Materials, Yokohama, 1991, pp. 68-70.
	Yadid-Pecht et al., "A Random Access Photodiode Array for Intelligent Image Capture", <u>IEEE Transactions on Electron Devices</u> , Vol. 38, No. 8 August 1991.
	Ricquier et al., "Pixel Structure with Logarithmic Response for Intelligent and Flexible Imager Architectures" <u>Microelectronic Engineering</u> , 19 (1992), pp. 631-634
	Sevenhans, et al., "A 400mm Long Linear X-Ray Sensitive Image Sensor", <u>IEEE International Solid-State Circuits Conference</u> , 1987, pp. 108-109.
	Anderson, S. et al., "A Single Chip Sensor & Image Processor or Fingerprint Verification", <u>IEEE 1991 Custom Integrated Circuits Conference</u> , May 12-15, 1991, pp. 12.1.1-12.1.4.
	Dierickx, Bart, "XYW Detector: A Smart Two-Dimensional Particle Sensor", <u>Nuclear Instruments and Methods in Physics Research A275</u> , North-Holland Physics Publishing Division, 1989, pp. 542-544.
	Klein, P., "Design and Performance of Semiconductor Detectors with Integrated Amplification and Charge Storage Capability", <u>Nuclear Instruments and Methods in Physics Research A305</u> , 1991, pp. 517-526.
	Aw, Chye Huat, et al., "A 128 x 128-Pixel Standard-CMOS Image Sensor with Electronic Shutter", <u>IEEE Journal of Solid State Circuits</u> , Vol.31, No. 12, December 1996, pp. 1922-1930.
Martin, W.J. et al., "Dynamic Offset Null", <u>IBM Technical Disclosure Bulletin</u> , No. 23, No. 9, February 1981, pp. 4195-4196.	

EXAMINER 	DATE CONSIDERED 6/00
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	

